IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Publications/Services Standards Conferences Careers/Jobs Welcome **United States Patent and Trademark Office** FAQ Terms IEEE Peer Review Quick Links Welcome to IEEE Xplore® O- Home Your search matched 24 of 1043368 documents.)- What Can A maximum of 500 results are displayed, 15 to a page, sorted by Relevance I Access? **Descending** order. O- Log-out **Refine This Search: Tables of Contents** You may refine your search by editing the current search expression or enteri new one in the text box. — Journals & Magazines (non\$1volatile<or>flash<or>eprom<or>eeprom<or>r Search Conference ☐ Check to search within this result set **Proceedings** O- Standards **Results Key:** JNL = Journal or Magazine CNF = Conference STD = Standard Search O- By Author O- Basic 1 Built in self test for low cost testing of a 60MHz synchronous flash memory ()- Advanced Mastrocola, V.; Palumbo, G.; Kumar, P.; Pipitone, F.; Introvaia, G.; On-Line Testing Workshop, 2001. Proceedings. Seventh International, 9-11] Member Services 2001 ()- Join IEEE Pages: 192 - 196 Establish IEEE Web Account [Abstract] [PDF Full-Text (304 KB)] **IEEE CNF** C - Access the 2 A 64-min single-chip voice recorder/player using embedded 4-b/ce **IEEE Member** flash memory Digital Library Borgatti, M.; Rocchi, A.; Bisio, M.; Besana, M.; Navoni, L.; Rolandi, P.L.; Solid-State Circuits, IEEE Journal of , Volume: 36 , Issue: 3 , March 2001 Print Format Pages: 516 - 521

> [Abstract] [PDF Full-Text (136 KB)] IEEE JNL

3 A P1500-compatible programmable BIST approach for the test of embedded flash memories

Bernardi, P.; Rebaudengo, M.; Reorda, M.S.; Violante, M.; Design, Automation and Test in Europe Conference and Exhibition, 2003, 200 Pages:720 - 725

[Abstract] [PDF Full-Text (KB)] **IEEE CNF**

4 Flash memory built-in self-test using March-like algorithms Jen-Chieh Yeh; Chi-Feng Wu; Kuo-Liang Cheng; Yung-Fa Chou; Chih-Tsun Hu Cheng-Wen Wu;

Electronic Design, Test and Applications, 2002. Proceedings. The First IEEE International Workshop on , 29-31 Jan. 2002

Pages:137 - 141

[Abstract] [PDF Full-Text (255 KB)] IEEE CNF

5 Records of the IEEE International Workshop on Memory Technology Design and Testing

High-Performance Distributed Computing, 2000. Proceedings. The Ninth International Symposium on , 1-4 Aug. 2000

[Abstract] [PDF Full-Text (168 KB)] IEEE CNF

6 Oscillation built-in self test (OBIST) scheme for functional and structesting of analog and mixed-signal integrated circuits

Arabi, K.; Kaminska, B.;

Test Conference, 1997. Proceedings., International, 1-6 Nov. 1997 Pages: 786 - 795

[Abstract] [PDF Full-Text (824 KB)] IEEE CNF

7 An approach to the analysis of the current testability of IC analog sections

Mateo, D.; Roca, M.; Serra-Graells, F.; Rubio, A.; Test Symposium, 1993., Proceedings of the Second Asian , 16-18 Nov. 1993 Pages:82 - 87

[Abstract] [PDF Full-Text (432 KB)] IEEE CNF

8 A 64 min single-chip voice recorder/player using embedded 4 bit/c flash memory

Borgatti, M.; Rocchi, A.; Bisio, M.; Besana, M.; Navoni, L.; Rolandi, P.L.; Custom Integrated Circuits Conference, 2000. CICC. Proceedings of the IEEE 2000, 21-24 May 2000 Pages:219 - 222

[Abstract] [PDF Full-Text (288 KB)] IEEE CNF

9 A 20 MB/s data rate 2.5 V flash memory with current-controlled fielerasing for 1 M cycle endurance

Dallabora, M.; Villa, C.; Caser, F.T.; Schippers, S.; Sali, M.; Ortolani, G.; Ger. A.; Defendi, M.; Cane, M.; Bettini, L.; Bartoli, S.; Cantarelli, D.; Bez, R.; Solid-State Circuits Conference, 1997. Digest of Technical Papers. 44th ISSC(1997 IEEE International, 6-8 Feb. 1997 Pages: 396 - 397, 492

[Abstract] [PDF Full-Text (1332 KB)] IEEE CNF

10 A configurable built in current sensor for mixed signal circuit testir *Picos, R.; Font, J.; Isern, E.; Roca, M.; Garcia, E.;*On-Line Testing Symposium, 2003. IOLTS 2003. 9th IEEE, 7-9 July 2003 Pages:167

[Abstract] [PDF Full-Text (294 KB)] IEEE CNF

11 A modified histogram approach for accurate self-characterization (analog-to-digital converters

Parthasarathy, K.L.; Le Jin; Degang Chen; Geiger, R.; Circuits and Systems, 2002. ISCAS 2002. IEEE International Symposium on , Volume: 2 , 26-29 May 2002 Pages:II-376 - II-379 vol.2

[Abstract] [PDF Full-Text (421 KB)]

12 Test and repair of embedded flash memories

Daga, J.M.;

Test Conference, 2002. Proceedings. International, 7-10 Oct. 2002 Pages:1219

[Abstract] [PDF Full-Text (181 KB)]

13 Diagonal test and diagnostic schemes for flash memories Sau-Kwo Chiu; Jen-Chieh Yeh; Chih-Tsun Huang; Cheng-Wen Wu; Test Conference, 2002. Proceedings. International, 7-10 Oct. 2002

Pages:37 - 46

[Abstract] [PDF Full-Text (515 KB)] **IEEE CNF**

14 Proceedings of the 2002 IEEE International Workshop on Memory Technology, Design and Testing (MTDT2002)

Memory Technology, Design and Testing, 2002. (MTDT 2002). Proceedings of 2002 IEEE International Workshop on , 10-12 July 2002 [Abstract] [PDF Full-Text (436 KB)] IEEE CNF

15 A code transition delay model for ADC test

Mohan, S.; Bushnell, M.L.;

VLSI Design, 2001. Fourteenth International Conference on, 3-7 Jan. 2001

Pages: 274 - 282

[Abstract] [PDF Full-Text (476 KB)] **IEEE CNF**

1 2 Next

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ | Terms | Back to Top

Copyright © 2004 IEEE - All rights reserved